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PATENT 5-14-02

03345-P0017A WWW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants	Michael Heuken, et al.
Serial No. 09/873,041	Filing Date: June 1, 2001
Title of Application:	Method And System For Semiconductor Crystal Production With Temperature Management
Group Art Unit: 2812/765	

Assistant Commissioner for Patents
Washington, DC 20231

Information Disclosure Statement by Applicants

Dear Sir:

As a means of complying with duty of disclosure set forth in 37 CFR 1.56,
Applicants list the following references (copies of the listed patents and
papers enclosed).

RECEIVED
MAY - 8 2002
TECHNOLOGY CENTER 8800

RECEIVED
MAY 13 2002
TC 1700

U.S. Patent Documents				
Exam. Initials	Class/ Subclass.	Document No.	Date	Name
MS	118/725	5,070,815	12/1991	Kasai et al.
	427/255.2	5,378,501	01/1995	Foster et al.
	427/8	5,614,247	03/1997	Barbee et al.
✓	118/715	5,755,886	05/1998	Wang et al.

Foreign Patent Documents			
Exam. Initials	Document No.	Date	Country
MS :	WO 97/08356	1997	PCT (US)

Other Documents	
Exam. Initials	Description (Author, Title, Date, Pages, etc)
MS	H. Jürgenson, D. Schmitz, G. Strauch, E. Woelk (all Aixtron AG) and M. Dauelsberg, L. Kadinski, Yu. N. Mararov (all University of Erlangen-Nürnberg); MOCVD EQUIPMENT FOR RECENT DEVELOPMENTS TOWARDS THE BLUE AND GREEN SOLID STATE LASER; June 22, 1996; 14 pg
	D. Schmitz, E. Woelk, G. Strauch, M. Deschler, H. Jürgenson; MOVPE GROWTH OF InGaN ON SAPPHIRE USING GROWTH INITIATION CYCLES; 1997; 9 pg
	R. Beccard, R. Niebuhr, B. Wachtendorf, D. Schmitz, H. Jürgensen; MULTIWAFFER MOVPE TECHNOLOGY FOR LOW DIMENSIONAL Ga-Al-In-N STRUCTURES; 1998; pgs 39-43

The listed patents pertain in a general way to the subject matter of the application, but are not necessarily considered to be analogous prior art.

Respectfully submitted,



May 1, 2002

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1/2/2003
Date/Considered

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Examiner